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Testing of multi-output circuits by means of signature analyzer

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Abstract

Let a circuit have m outputs, m>1. There are two ways to test this circuit by means of a signature analyzer: use a single input analyzer for each output or use an m-input analyzer to test all outputs simultaneously. The main goal of this letter is to demonstrate that for fault output sequences with small multiplicity of errors and long length the second approach is more effective. © 1993 Kluwer Academic Publishers.

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Keywords

Data compaction, multiple input analyzer